Application of a HEPE-oriented 4096-MAPS to time analysis of single electron distribution in a two-slits interference experiment

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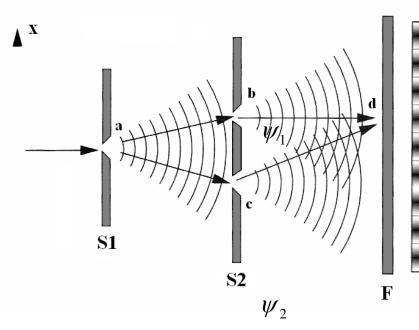
Outline

- Young's experience with single electrons
- Double slit, one electron at a time
- Instrumentation
 - Electron Microscope TEM
 - Double slit
 - APSEL4D MAPS sensor
- Measurements of diffraction by a grating
- Measurements of interference
- Conclusion

Young's Interference

Basics

- Monochromatic source λ , $\lambda_{\text{De Broglie}} = h/p$
- Two slits at a distance **d** create coherent waves
- Screen at a distance D >> d

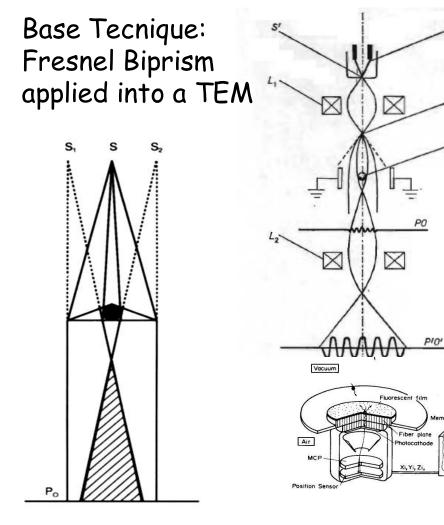


$$P(x) = |\psi_1 + \psi_2|^2 = |\psi_1|^2 + |\psi_2|^2 + 2\operatorname{Re}\psi_1^*\psi_2$$

R. Feynmann: - Lecture on Physics, Vol 3

Young's experiment with the electrons can only be conceptual in nature because of the smallness of the de Broglie wavelength

Young's Interference Past Experiments

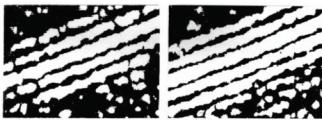


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Esperiments in literature Merli, Missiroli, Pozzi (1976) A. Tonomura et al. (1989)

single electron conditions



Demonstration: Wave character of the electron

The base interference is that of an **electron with itself**

Physics World (2002): The most beautiful experiment in physics, according to a poll of *Physics World* readers, is the interference of single electrons in a Young's double slit. Robert P Crease reports

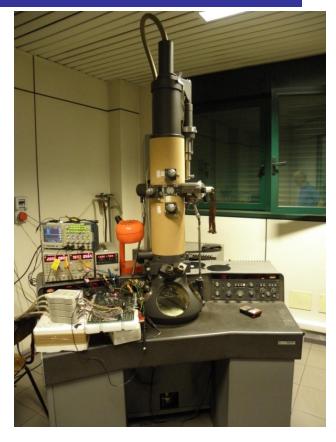
Instrumentation

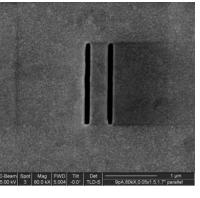
- TEM Philips M400T (120 keV max)
- Two nanometric slits

 4096 MAPs Sensor ST 130nm CMOS

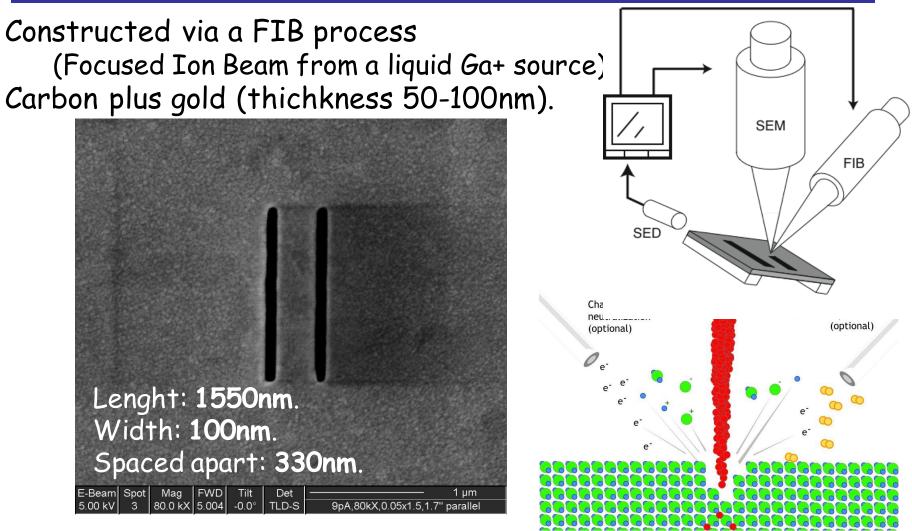
DAQ system

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The two slits



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The APSEL4D MAPS sensor

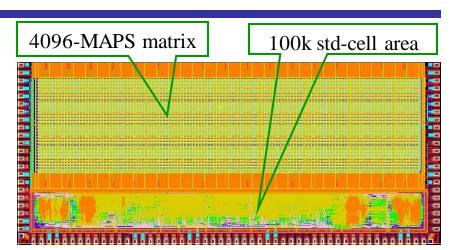
R&D project for HEPE → Vertex detector oriented to the SuperB project Technology ST 130 nm

Readout:

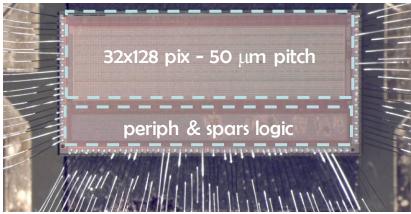
Data Driven Sparsification logic Optimized for charged particle identification

Output infos: z: thickness 300 µm x,y: spatial resolution 15 µm t: time resolution (BCO) > 0.4 µs Clock frequency: 20-50 MHz

Efficiency measured with 12 GeV proton beam at CERN: ≈ 90%

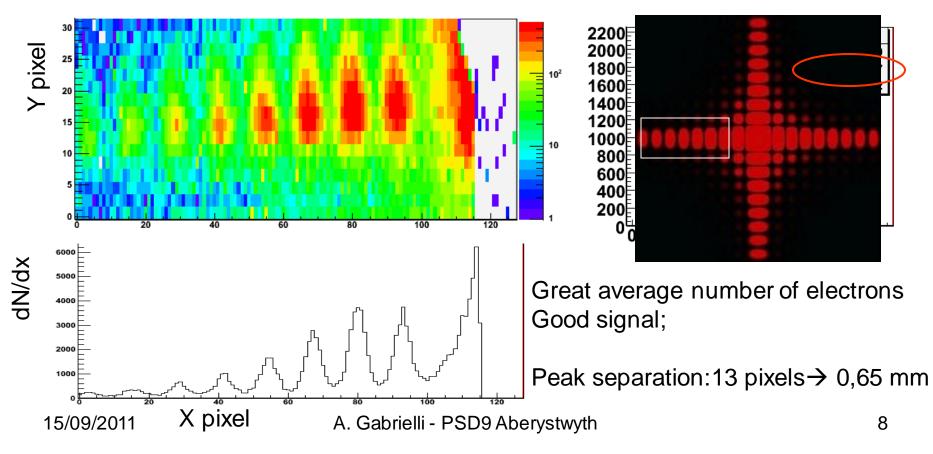


Squared Pixels 50 x 50 µm Sensitive Area : 6.4 mm x 1.6 mm

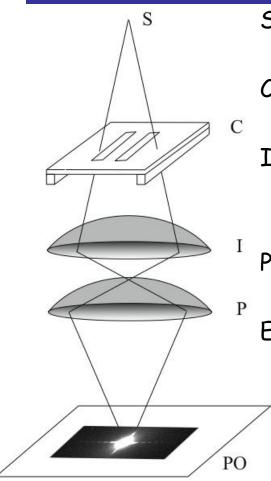


Carbon Grating Diffraction

Carbon diffraction grating: pitch 400 nm typical 40-60 keV electrons: $\lambda = h/p = 5-6$ pm, typical angle 10⁻⁵ rad Observation windows: 3-7 ms



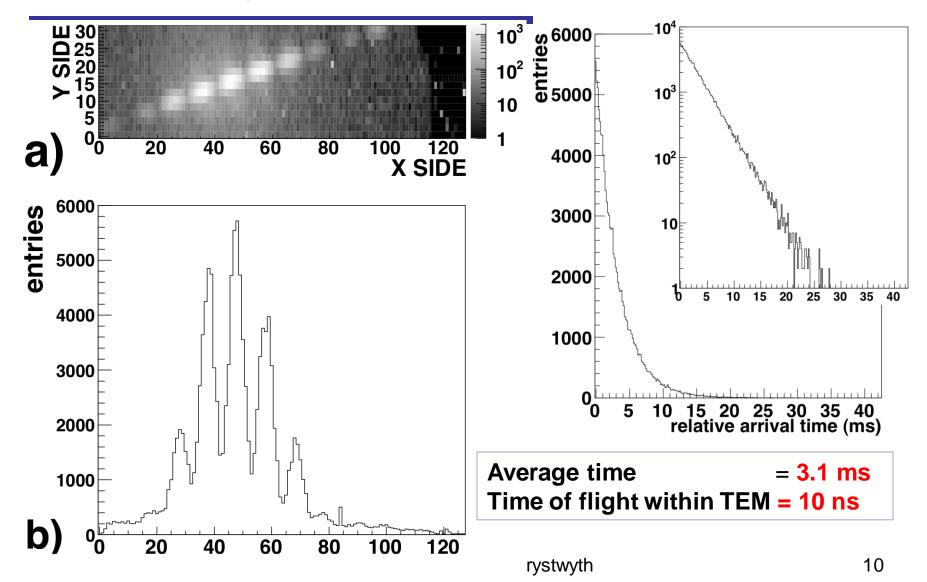
Set-up inside the TEM



- S- Small size source
- C Sample with two slits
- I,P Image and projection lenses
- PO: projection plane
- Experimental conditions: Fraunhofer regime (plane wave approximation)

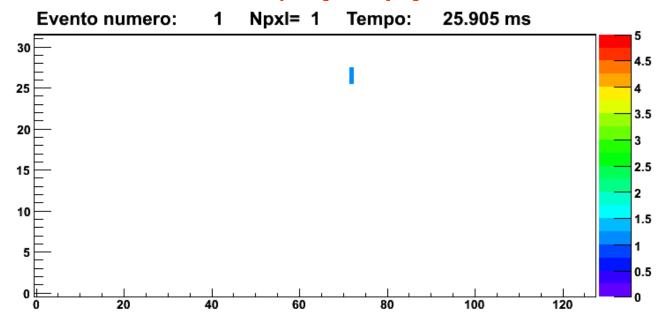


The single-electron interference I



The single-electron interference II

Double slit: distance d=300 nm 40-60 keV electrons: $\lambda = h/p = 5-6$ pm, typical angles 10⁻⁵ rad; v=0,4 c Observation windows 165 µs (6k fps)

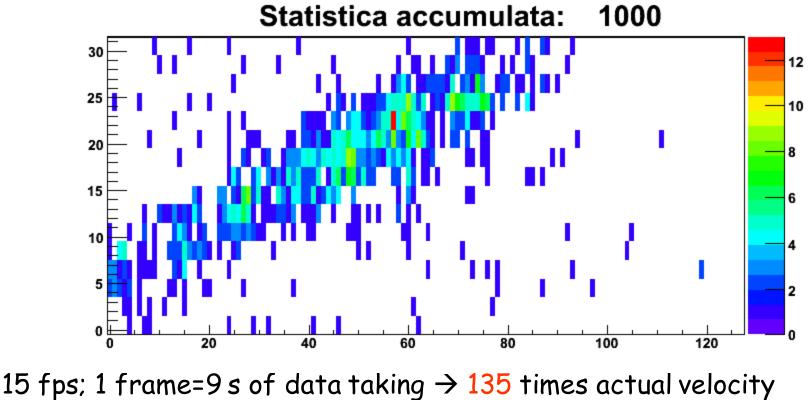


15 full frames per second \rightarrow 1 / 7 Actual speed

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The single-electron interference III

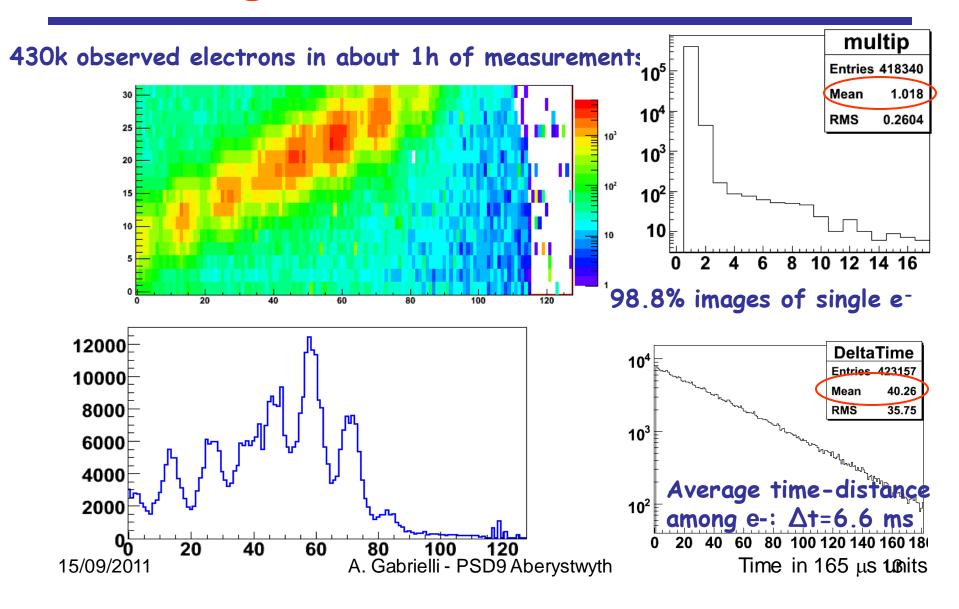
Double slit: distance d=300 nm 40-60 keV electrons: $\lambda = h/p = 5-6$ pm, typical angles 10^{-5} rad; v=0,4 c Observation windows 165 µs (6k fps)



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The single-electron interference IV



Conclusion

- Used for the first time a system of nano-slits with a high timeperformance sensor
- (4096 pixels, 6k fps→2M fps) developed by INFN via a R&D project oriented to the next generation of silicon trackers (SLIM5).
- Reconstructed the Young interference with single electrons
 - Significant conceptual clarity to show the wave behavior of single electrons
- 98.8% of frames with single electrons. Average time among electrons has been measured to: 3 - 7 ms.
- The sensor APSEL4D worked very well in a way not initially expected. The temporal characteristics can be used in a new field of electron microscopy: the study of static phenomena.

Thanks to the SLIM5 collaboration